

Special Topics on Basic EECS I Design Technology Co-Optimization

Lecture 5

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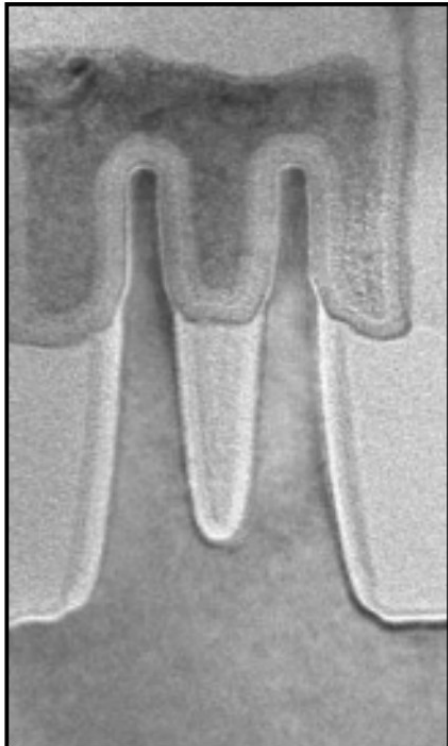
Gwangju Institute of Science and Technology (GIST)

L5

Intel 14 nm @ IEDM 2014

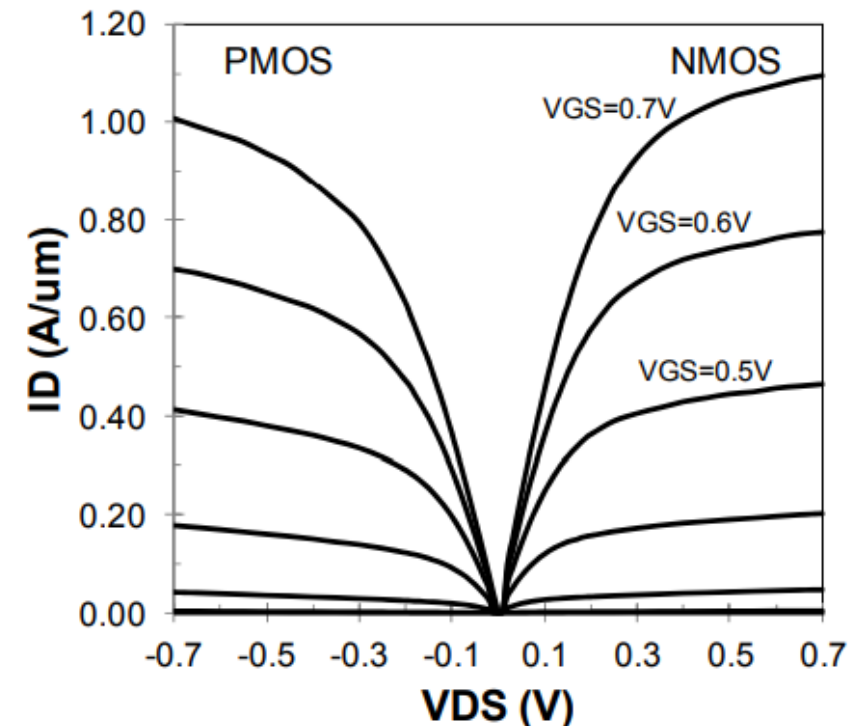
- 16 years later,
 - First of all, it is not a planar MOSFET but a FinFET.
 - Fin pitch is 42 nm. Contacted gate pitch is 70 nm.
 - Gate length is 20 nm. SRAM: $0.0588 \mu\text{m}^2$

Transistor
fin image
(Intel)



Transistor
IV curves
(Intel)

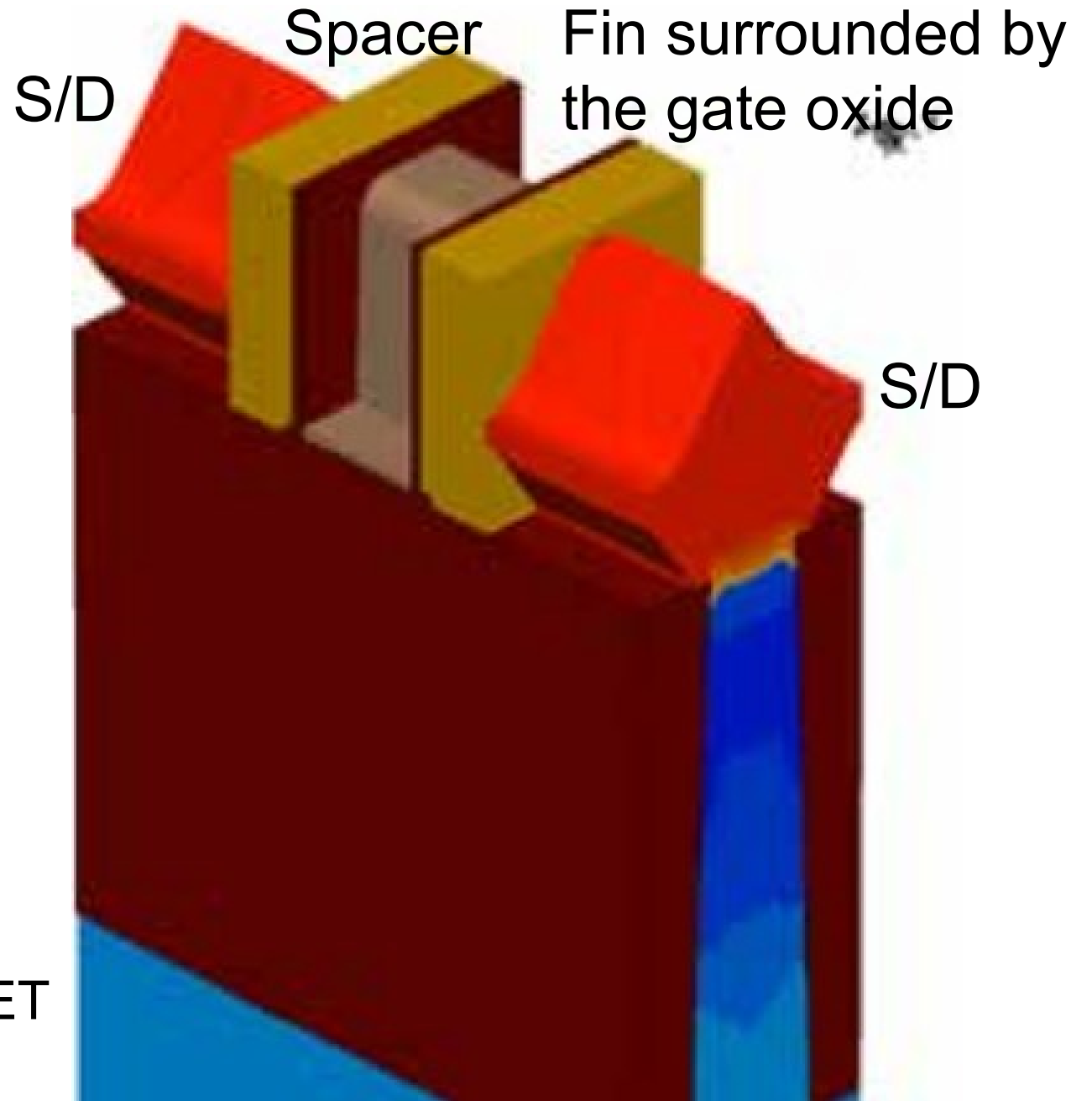
GIST Lecture



FinFET

- A tall fin
 - “Tri-gate” by Intel
 - It’s like a double-gate.
- Then, why double-gate?
 - Better gate controllability
(We all know it.)

3D structure of a FinFET transistor (Synopsys)



Lesson from “VLSI Devices” (1)

For your interest, watch the video, [Eng][VLSIDevices2025] L16, L17, and L18

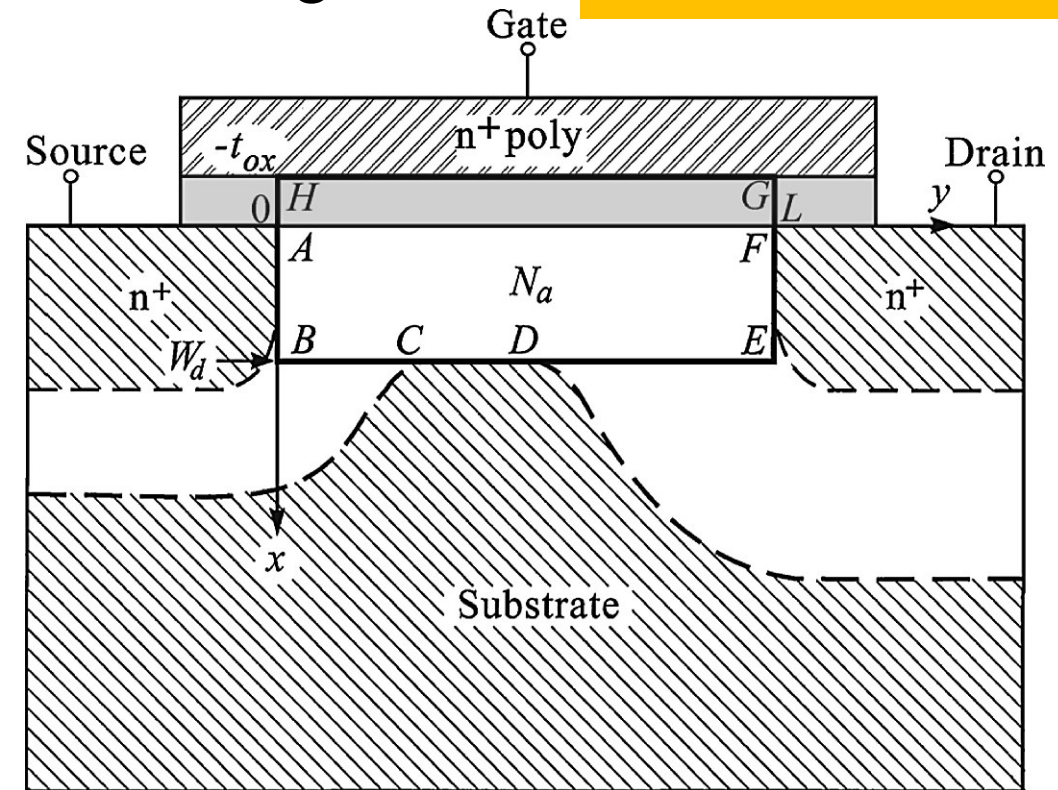
- In the subthreshold regime, we may solve
 - The Poisson equation without inversion charges

$$\frac{\partial^2 \phi}{\partial x^2} + \frac{\partial^2 \phi}{\partial y^2} = -\frac{qp(x, y)}{\epsilon_{si}} + \frac{qN_a}{\epsilon_{si}}$$

- Hole density is a nonlinear function of $\phi(x, y)$.

- It can be neglected in the depletion region.

$$\frac{\partial^2 \phi}{\partial x^2} + \frac{\partial^2 \phi}{\partial y^2} = \frac{qN_a}{\epsilon_{si}}$$



Planar MOSFET
(Prof. Taur's book)

Lesson from “VLSI Devices” (2)

For your interest, watch the video, [Eng][VLSIDevices2025] L16, L17, and L18

- Boundary conditions by terminal voltages

- Try the following function:

$$\phi(x, y) = v(x, y) + u_L(x, y) + u_R(x, y) + u_B(x, y)$$

Poisson equation
with upper b.c.
(Long-channel)

Laplace equation
to match left b.c.

Laplace equation
to match right b.c.

Laplace equation to
match bottom b.c.

- Then,

$$\frac{\partial^2 u_R}{\partial x^2} + \frac{\partial^2 u_R}{\partial y^2} = 0$$

Lesson from “VLSI Devices” (3)

For your interest, watch the video, [Eng][VLSIDevices2025] L16, L17, and L18

- Solution of Laplace equation
 - Separation of variables

$$u_R(x, y) = X(x)Y(y)$$

– When $\frac{d^2 X}{dx^2} = -\frac{1}{\lambda^2} X$ and $\frac{d^2 Y}{dy^2} = \frac{1}{\lambda^2} Y$,

$$\frac{d^2 X}{dx^2} Y + X \frac{d^2 Y}{dy^2} = 0$$

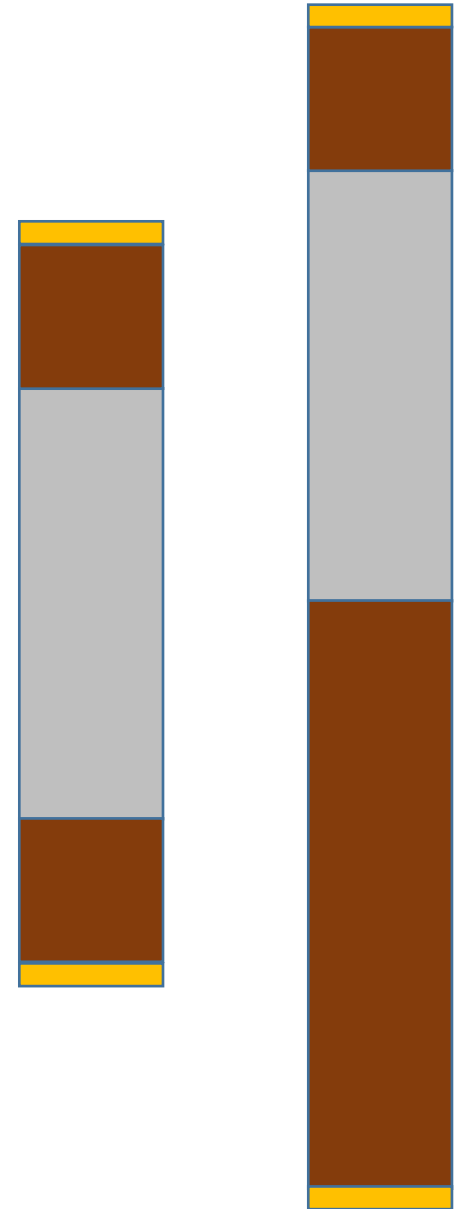
Exponential functions

Sinusoidal functions

- The vertical variation and the lateral variation are coupled.

Compare two structures.

- Calculate λ for two structures
 - 1) Double-gate (from $x = -\frac{t_{si}}{2}$ to $x = \frac{t_{si}}{2}$)
 - Top- and bottom-gates
 - Symmetric about $x = 0$
 - 2) (Almost) single-gate (from $x = 0$ to $x = t_{si}$)
 - Only top-gate
 - Vanishing electric field at $x = 0$




Boundary condition

- Continuity of displacement @ Si/SiO₂ interface
 - Assume that u_R is a homogeneous solution induced by the drain voltage.
 - 1) Double-gate

$$\epsilon_{si} \frac{\partial u_R}{\partial x} \bigg|_{x=\frac{t_{si}}{2}, y} = -\epsilon_{ox} \frac{u_R \left(x = \frac{t_{si}}{2}, y \right)}{t_{ox}}$$

Vertical
components
only



- 2) Single-gate

$$\epsilon_{si} \frac{\partial u_R}{\partial x} \bigg|_{x=t_{si}, y} = -\epsilon_{ox} \frac{u_R(x = t_{si}, y)}{t_{ox}}$$

Boundary condition for $X(x)$

- Recall $u_R(x, y) = X(x)Y(y)$.

– 1) Double-gate

$$\epsilon_{si} \frac{dX}{dx} \Big|_{x=\frac{t_{si}}{2}, y} \cancel{Y} = -\epsilon_{ox} \frac{X\left(x = \frac{t_{si}}{2}\right) \cancel{Y}}{t_{ox}}$$

– 2) Single-gate

$$\epsilon_{si} \frac{dX}{dx} \Big|_{x=t_{si}, y} \cancel{Y} = -\epsilon_{ox} \frac{X(x = t_{si}) \cancel{Y}}{t_{ox}}$$

– In both cases, $\frac{dX}{dx} = -\frac{\epsilon_{ox}}{\epsilon_{xi} t_{ox}} X$ at Si/SiO₂ interface.

Double-gate

- Due to symmetry, $X(x) = \cos \frac{x}{\lambda}$. (Sine function is not possible.)

$$-\epsilon_{si} \frac{1}{\lambda} \sin \frac{t_{si}}{2\lambda} = -\epsilon_{ox} \frac{\cos \frac{t_{si}}{2\lambda}}{t_{ox}}$$

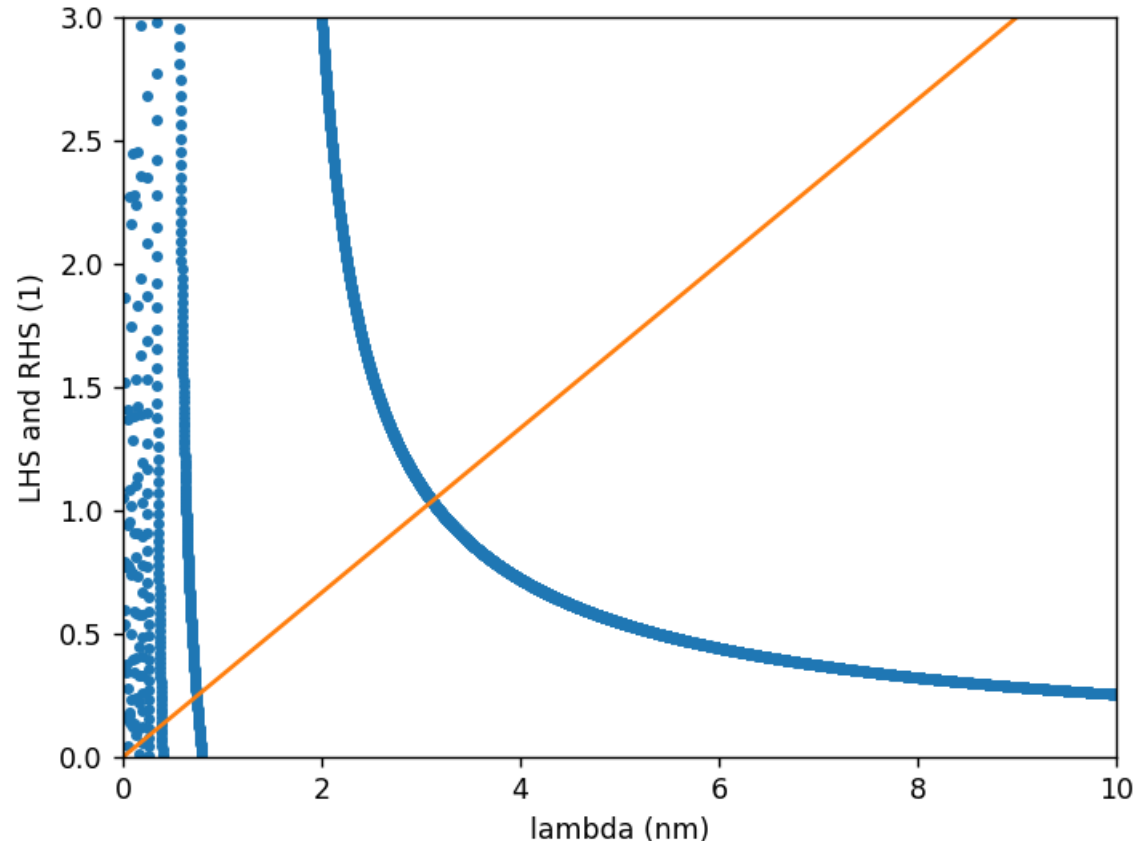
$$\tan \frac{t_{si}}{2\lambda} = \frac{\epsilon_{ox}}{\epsilon_{si} t_{ox}} \lambda$$

–An example)

$t_{si} = 5$ nm and $t_{ox} = 1$ nm

ϵ_{si} is three times ϵ_{ox} .

→ Largest λ is 3.111 nm.



Single-gate

- Again, due to the boundary condition at $x = 0$, $X(x) = \cos \frac{x}{\lambda}$. (Sine function is not possible.)

$$-\epsilon_{si} \frac{1}{\lambda} \sin \frac{t_{si}}{\lambda} = -\epsilon_{ox} \frac{\cos \frac{t_{si}}{\lambda}}{t_{ox}}$$

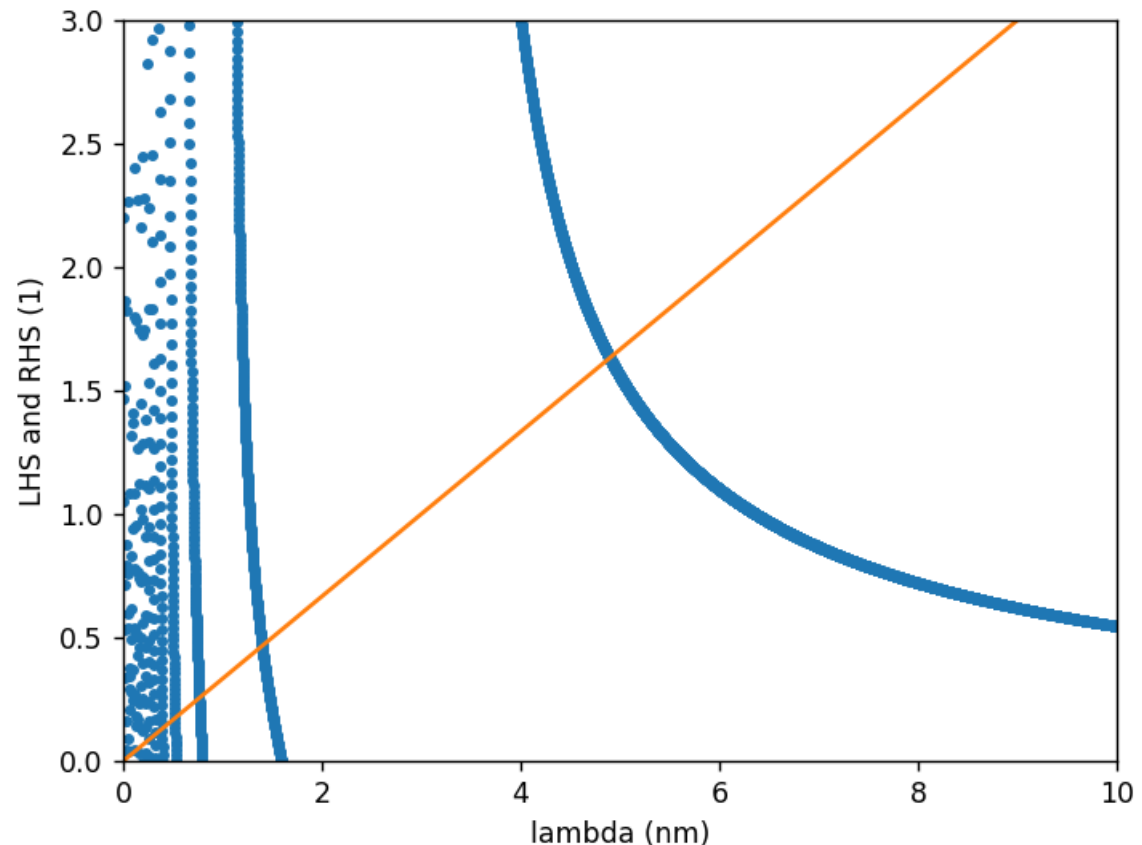
$$\tan \frac{t_{si}}{\lambda} = \frac{\epsilon_{ox}}{\epsilon_{si} t_{ox}} \lambda$$

–An example)

$t_{si} = 5$ nm and $t_{ox} = 1$ nm

ϵ_{si} is three times ϵ_{ox} .

→ Largest λ is 4.897 nm.



Approximate expressions

- Two structures share the same expression.

$$\tan \frac{t_{si}}{\textcolor{red}{N}\lambda} = \frac{\epsilon_{ox}}{\epsilon_{si}t_{ox}} \lambda$$

- Although not perfect (as shown in our example), it is frequently approximated as

$$\frac{t_{si}}{\textcolor{red}{N}\lambda} = \frac{\epsilon_{ox}}{\epsilon_{si}t_{ox}} \lambda$$
$$\lambda = \sqrt{\frac{\epsilon_{si}}{\textcolor{red}{N}\epsilon_{ox}}} t_{si} t_{ox}$$

- This expression yields 2.7 nm (DG) and 3.9 nm (SG), respectively.

Thank you!